

Search Notes**Application/Control No.**

10/731,503

Examiner

Steven J. Fulk

Applicant(s)/Patent under Reexamination

WU, SHYE-LIN

Art Unit

2891

SEARCHED

Class	Subclass	Date	Examiner
257	471	2/2/2006	SJF
257	473	2/2/2006	SJF
257	475	2/2/2006	SJF
257	483	2/2/2006	SJF
257	484	2/2/2006	SJF
257	485	2/2/2006	SJF
438	534	2/2/2006	SJF
438	575	2/2/2006	SJF
438	576	2/2/2006	SJF

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PG Pubs	Claims	2/2/2006	SJF

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
438/1+; 257/1+ (text search only - see search history printout)	2/2/2006	SJF
IEEE Xplore - see search history printout	2/2/2006	SJF